## Search Notes



Application/Control No.

Applicant(s)/Patent Under Reexamination

09663968

YIP, PING

Examiner

Skowronek, Karlheinz R

Art Unit

1631

Notes	Date		Examiner
Search Terms: MASS SPEC, DATA ANALYSIS, AUTOMATED,COMPUTER, DENOISE, WAVELET FRANSFORMATION,RESIDUAL BASELINE,MOVING AVERAGE BASELINE, DNA, TIME OF FLIGHT, NOISE REMOVAL, PEAK SUBTRACTION: Inventor search	09/11/2006	KRS	
AST:Search Terms	09/11/2006	KRS	
STN:MEDLINE, CAPLUS, BIOSIS,EMBASE,PASCAL,SCISEARCH; Search Terms	09/11/2006	KRS	
U.S. Patent and Trademark Office		Part of Paper No.:	20060908

